

Notice of References Cited

Application/Control No.

10/828,437

Applicant(s)/Patent Under
Reexamination
ENDOH ET AL.

Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0005252	01-2002	MASUDA et al.	156/345
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02/065532	08-2002	Japan	Nishikawa	H01L 21/3065
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

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